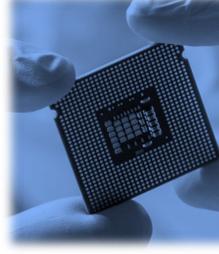




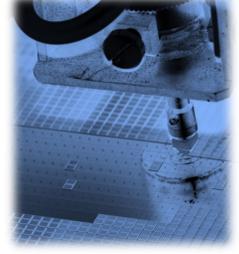
FAB



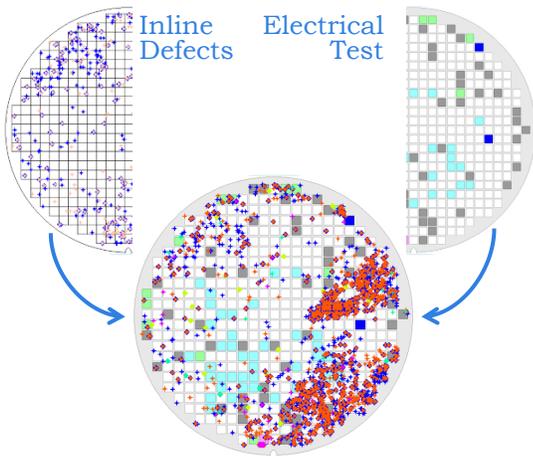
WAFER SORT



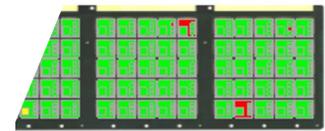
ASSEMBLY



TEST



Strip Maps
Tray Maps
Panel Maps



End-to-End Defect and Yield Data



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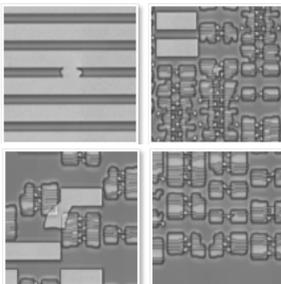
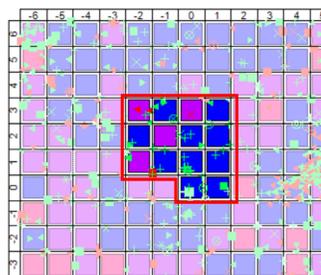
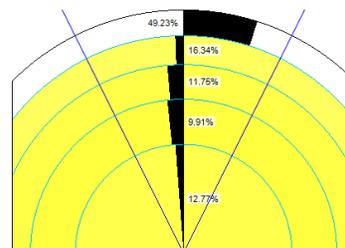


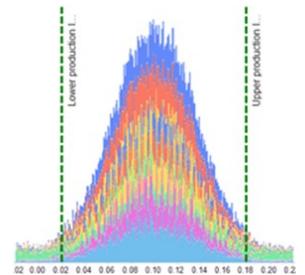
Image Gallery



Stacked Defect Maps



Zonal Maps



Charts and Plots

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